



**Underwriters
Laboratories UL Japan, Inc.**

Test report No. : 29GE0111-HO-01-A-R1
Page : 1 of 34
Issued date : May 28, 2009
Revised date : June 15, 2009
FCC ID : XBXBC5849501

RADIO TEST REPORT

Test Report No. : 29GE0111-HO-01-A-R1

Applicant : TANITA Corporation

Type of Equipment : RF module

Model No. : BC5849501

FCC ID : XBXBC5849501

**Test standard : FCC Part 15 Subpart C 2009
Section 15.207, Section 15.249**

Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. Original test report number of this report is 29GE0111-HO-01-A.

Date of test:

May 18 and 19, 2009

Tested by:

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<u>CONTENTS</u>	<u>PAGE</u>
SECTION 1: Customer information.....	3
SECTION 2: Equipment under test (E.U.T.).....	3
SECTION 3: Test specification, procedures & results.....	4
SECTION 4: Operation of E.U.T. during testing.....	8
SECTION 5: Conducted Emission.....	10
SECTION 6: Spurious Emission	11
SECTION 7: Bandwidth and Duty Cycle.....	12
APPENDIX 1: Photographs of test setup.....	13
Conducted Emission	13
Spurious Emission (Radiated)	14
Worst Case Position (Horizontal: Z-axis/ Vertical:X-axis).....	15
APPENDIX 2: Data of EMI test.....	16
Conducted Emission	16
20dB Bandwidth	21
Radiated Spurious Emission (below 1GHz)	23
Transmitting Specification (Duty Cycle)	27
Electric Field Strength of Fundamental and Spurious Emission (above 1GHz).....	28
99%Occupied Bandwidth	33
APPENDIX 3:Test instruments	34

Test report No.	: 29GE0111-HO-01-A-R1
Page	: 3 of 34
Issued date	: May 28, 2009
Revised date	: June 15, 2009
FCC ID	: XBXBC5849501

SECTION 1: Customer information

Company Name : TANITA Corporation
Address : 1-14-2 Maeno-cho Itabashi-ku Tokyo, 174-8630 Japan
Telephone Number : +81-3-3968-2179
Facsimile Number : +81-3-3968-1550
Contact Person : Akinori Ochiai

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : RF module
Model No. : BC5849501
Serial No. : MP001
Rating : DC3.2V - DC10.0V
Country of Manufacture : Japan
Receipt Date of Sample : May 18, 2009
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No modification by the test lab.

2.2 Product Description

Model No: BC5849501 (referred to as the EUT in this report) is the RF module.
It is used for data transmission of the measurement machinery.

General Specification

Clock frequency(ies) in the system : CPU:1MHz, 32.768kHz RFIC:16MHz

Radio Specification

Equipment Type : Transceiver
Frequency of Operation : 2405MHz - 2479MHz
Channel Spacing : 1MHz
Modulation : GFSK
Antenna Type : Chip antenna
Antenna Gain : -2.5dBi
Method of Frequency Generation : Crystal

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Test report No. : 29GE0111-HO-01-A-R1
Page : 4 of 34
Issued date : May 28, 2009
Revised date : June 15, 2009
FCC ID : XBXBC5849501

SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2009, final revised on February 27, 2009

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.249 Operation within the bands 902-928MHz, 2400-2483.5MHz, 5725-5875MHz and 24.0-24.25GHz

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3.2 Procedures and results

No.	Item	Test Procedure	Specification	Deviation	Worst margin	Results
1	Conducted Emission	ANSI C63.4:2003 7. AC powerline conducted emission measurements	Section 15.207(a)	N/A	[QP] 38.6dB (29.83230MHz, N) [AV] 37.7dB (29.83230MHz, N)	Complied
2	Electric Field Strength of Fundamental Emission	ANSI C63.4:2003 13. Measurement of intentional radiators	Section 15.249(a)(e)	N/A	14.7dB (2405.0MHz, Hori., PK)	Complied
3	Electric Field Strength of Spurious Emission	ANSI C63.4:2003 13. Measurement of intentional radiators	Section 15.205(a)(b) Section 15.209(a) Section 15.249(a)(d)(e)	N/A	[Tx] 4.6dB (2445.9MHz, Hori., PK) [Rx] 6.7dB (34.812MHz, Ver., QP)	Complied
4	20dB Bandwidth	ANSI C63.4:2003	Reference	N/A	N/A	N/A
5	Frequency Tolerance	ANSI C63.4:2003	Section 15.249(b)	N/A	N/A	N/A *1)

*Note: UL Japan, Inc.'s EMI Work Procedure QPM05.

*1) The test is not required since this EUT does not operate with 24.05GHz to 24.25GHz.

*These tests were performed without any deviations from test procedure except for additions or exclusions.

*In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

FCC 15.31 (e)

This EUT provides stable voltage(DC3.0V) constantly to RF part regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203/212 Antenna requirement

The antenna is not removable from the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.3 Addition to standards

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied Bandwidth	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	Conducted	N/A	N/A	N/A

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (\pm dB)	
	150kHz-30MHz	
No.1	3.7dB	
No.2	3.7dB	
No.3	3.7dB	
No.4	3.7dB	

Test room (semi-anechoic chamber)	Radiated emission (10m*)(\pm dB)			Radiated emission (3m*)(\pm dB)					
	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	1GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz
No.1	3.1dB	4.4dB	3.9dB	3.2dB	3.8dB	3.9dB	5.0dB	5.0dB	5.4dB
No.2	-	-	-	3.2dB	4.4dB	4.0dB	5.0dB	5.2dB	5.4dB
No.3	-	-	-	3.2dB	4.2dB	3.8dB	5.0dB	5.3dB	5.3dB
No.4	-	-	-	3.2dB	4.0dB	3.8dB	5.0dB	5.3dB	5.3dB

*10m/3m = Measurement distance

Power meter (\pm dB)	
Below 1GHz	Above 1GHz
1.0dB	1.0dB

Antenna terminal conducted emission and Power density (\pm dB)			Antenna terminal conducted emission (\pm dB)		Channel power (\pm dB)
Below 1GHz	1GHz-3GHz	3GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz	
1.0dB	1.1dB	2.7dB	3.2dB	3.3dB	1.5dB

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m/1m)

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

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3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Test instruments and Data of EMI

Refer to APPENDIX 1 to 3.

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SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Transmitting (Tx), 10101010 binary data x 8 bytes

Receiving (Rx)

*The details of Operating Mode(s)

Test Item	Mode	Tested frequency
Conducted Emission, Spurious Emission (Conducted/Radiated)	Transmitting (Tx) Receiving (Rx)	2405MHz 2440MHz 2479MHz 2440MHz
20dB Bandwidth	Transmitting (Tx)	2405MHz 2440MHz 2479MHz
Duty cycle	Transmitting (Tx)	2440MHz
99% Occupied Bandwidth	Transmitting (Tx)	2405MHz 2440MHz 2479MHz

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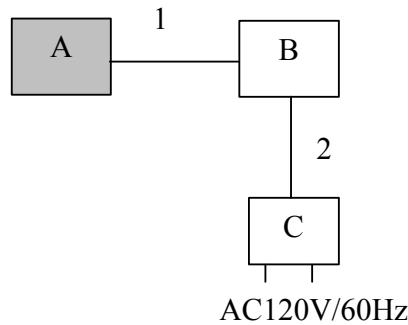
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4.2 Configuration and peripherals



* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	RF Module	BC5849501	MP001	TANITA Corporation	EUT
B	Jig	-	-	TANITA Corporation	-
C	AC Adapter	A20620N	-	SINO-AMERICAN	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	Signal Cable	0.5	Unshielded	Unshielded	-
2	DC Cable	1.9	Unshielded	Unshielded	-

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SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 0.5m, raised 80cm above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

1) For the tests on EUT with other peripherals (as a whole system)

I/O cable and AC cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber or a Measurement Room.

The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

Detector	: QP and AV
Measurement range	: 0.15-30MHz
Test data	: APPENDIX
Test result	: Pass

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SECTION 6: Spurious Emission

Test Procedure

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 0.8m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Biconical	Logperiodic	Horn

Frequency	Below 1GHz	Above 1GHz	
Instrument used	Test Receiver		Spectrum Analyzer
Detector	QP	PK	AV
IF Bandwidth	BW 120kHz(T/R)	RBW: 1MHz VBW: 1MHz	*1), *2)
Test Distance	3m		3m (below 10GHz), 1m*2) (above 10GHz), 0.5m*3) (above 26.5GHz)

*1) For Transmitter Spurious Emission test, emission was pulsed.

Therefore, the Average value was calculated by reducing Duty factor from PK (PK value - Duty factor).

For Duty factor, please refer to Page 27.

*2) For Receiver Spurious Emission test, the Average value was calculated as follows;

-For Pulse emission: Average Detector (RBW: 1MHz, VBW:110Hz)

The VBW is based on the inverse of the duty cycle for the investigated noise (see page 32).

-For Non-Pulse emission: Average Detector (RBW: 1MHz, VBW:10Hz)

*3) Distance Factor: $20 \times \log (3.0m/1.0m) = 9.5dB$

*4) Distance Factor: $20 \times \log (3.0m/0.5m) = 15.6dB$

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

Measurement range : 30M-25GHz
Test data : APPENDIX
Test result : Pass

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SECTION 7: Bandwidth and Duty Cycle

Test Procedure

The tests were made with below setting with Spectrum analyzer.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	3MHz	100kHz	300kHz	50ms	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Duty Cycle	Zero Span	1MHz	1MHz	Auto	Peak	Single	Spectrum Analyzer

The test results and limit are rounded off to two decimals place, so some differences might be observed.

Test data : APPENDIX
Test result : Pass